

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Applicant(s): Moshe Finarov; Eran Dvir; Eli Haimovich; Benjamin Shulman  
Assignee: Nova Measuring Instruments, Ltd.  
Title: APPARATUS FOR OPTICAL INSPECTION OF WAFERS DURING POLISHING  
Serial No.: Unknown Filed: Herewith  
Examiner: Unknown Group Art Unit: Unknown  
Docket No.: M-3417-2C US

San Jose, California  
February 4, 2000

BOX PATENT APPLICATION  
ASSISTANT COMMISSIONER FOR PATENTS  
WASHINGTON, D. C. 20231

Dear Sir:

**PRELIMINARY AMENDMENT**

This Paper is submitted prior to examination of the above-listed patent application, a Continuation of U.S. Patent Application Serial No. 08/497,382, filed on June 29, 1995, (hereinafter "the Parent Application"), which has been allowed.

Please amend the Patent Application as follows.

**IN THE DRAWINGS**

Please amend FIGS. 6, 7, 8 and 9 as indicated in red ink on the enclosed copies of those figures as filed in Parent Application.

**IN THE SPECIFICATION**

On page 1, immediately above FIELD OF THE INVENTION, insert the following section.

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